TOSHIBA PHOTOCOUPLER LED & PHOTO-IC

TLP708, TLP708F

Factory Automation (FA)
Home Electrical Appliances
Operates at high ambient temperature up to 125°C

The Toshiba TLP708 consists of an infrared emitting diode and an integrated highgain, high-speed photodetector. The TLP708 is housed in the SDIP6 package. Compared to the standard DIP8 package, TLP708 is smaller in size, yet comes with international safety standards under a reinforced isolation category. As such, it is possible to reduce the mounting footprint for applications that require certifications for safety standards.

The photodetector has an open-collector output stage, and an internal Faraday shield that provides a guaranteed common-mode transient immunity of ±15 kV/µs. As TLP708 is also able to operate up to 125°C, it is suitable for use in applications like industrial equipments where it is necessary to operate under high ambient temperature.

TLP708F is of a long creepage distance and clearance distance type.

• Input threshold current : IFHL = 5mA (max)

Switching time (t_{pHL}/t_{pLH}): 75ns (max)

Data transfer rate:
 15 MBd (typ.)

• Guaranteed Performance over temperature: -40 to 125 °C

Power supply voltage: 4.5 to 5.5 V

• Common mode transient immunity: ±15 kV /µs (min)

Isolation voltage: 5000 V_{rms} (min)

• Construction mechanical rating

d			
		7.62 mm Pitch TLP708 Type	10.16 mm Pitch TLP708F Type
	Creepage distance Clearance distance Insulation thickness	7.0 mm (min) 7.0 mm (min) 0.4 mm (min)	8.0 mm (min) 8.0 mm (min) 0.4 mm (min)

• UL-recognized: UL 1577, File No. E67349

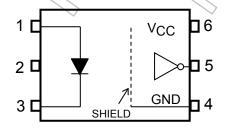
• cUL-recognized: CSA Component Acceptance Service No.5A

File No. E67349

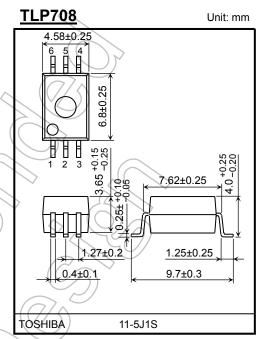
• VDE-approved: EN 60747-5-5, EN 62368-1 (Note 1)

Note 1: When a VDE approved type is needed, please designate the **Option (D4)**.

Pin Configuration (Top View)



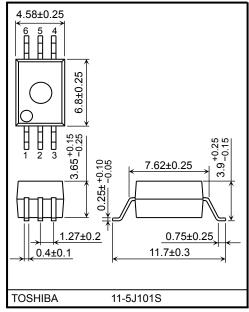
1:ANODE 2:N.C. 3:CATHODE 4:GND 5:V_O(Output) 6:V_{CC}



Weight: 0.26 g (typ.)

TLP708F

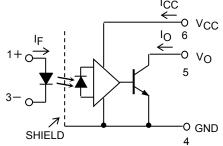
Unit: mm



Weight: 0.26 g (typ.)

Start of commercial production 2010-06

Schematic



Note: A $0.1\mu F$ bypass capacitor must be connected between pins 6 and 4.

Truth Table

Input	Output
Н	L
4	Н

Absolute Maximum Ratings (Ta = 25°C)

	Characteristics	Symbol	Rating	Unit	
	Forward Current	(Ta < 110°C)	lF	25	mA
	Forward Current Derating	(Ta ≥ 110°C)	ΔI _F /°C	-0.67	mA/°C
	Pulse Forward Current (Note 1)	(Ta < 110°C)	I _{FP}	50	mA
E	Pulse Forward Current Derating	(Ta ≥ 110°C)	ΔIFP/°C	-1.34	mA/°C
	Reverse Voltage	VR	5	\\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\	
	Input Power Dissipation	(Ta < 110°C)	PD	40	mW
	Input Power Dissipation Derating	t Power Dissipation Derating (Ta ≥ 110°C)		-1.0	mW/°C
	Output Current	(Ta ≤ 125°C)		25	mA
유	Output Voltage	Vo	6	V	
ETECTOR	Supply Voltage	Vcc	6	V	
ETE	Output Power Dissipation	(Ta < 110°C)	Po (80	mW
	Output Power Dissipation Derating	ΔPo/°C	2.0	mW/°C	
Оре	erating Temperature Range	Topr	T _{opr} -40 to 125		
Stor	rage Temperature Range	T _{stg} -55 to 150		°C	
Lea	d solder Temperature (10 s)	T _{sol}	260	°C	
Isola	ation voltage (Note 2)	BVs	s 5000		

Note: Using continuously under heavy loads (e.g. an application of high temperature/current/voltage and a significant change in temperature, etc.) may cause this product to decrease in reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc.)

Note 1: Pulse width \leq 1ms, duty = 50 %

Note 2: R.H. ≤ 60 %, Ta = 25 °C, AC 60 s

This device is regarded as a two-terminal device: pins 1, 2 and 3 are shorted together, and pins 4, 5 and 6 are shorted together.



Recommended Operating Condition

Characteristics	Symbol	Min	Тур.	Max	Unit
'L' level input voltage	VFL	0	_	0.8	V
'H' level input current	lFH	7.5	_	15	_mA
Supply voltage*	Vcc	4.5	_	5.5	V
Operating temperature range	Topr	-40		125	(C

^{*} This item denotes operating ranges, not meaning of recommended operating conditions.

Note: Recommended operating conditions are given as a design guideline to obtain expected performance of the device. In addition, each item is an independent guideline. In developing designs using this product, please confirm the specified characteristics shown in this document.

Electrical Characteristics

(Unless otherwise specified, Ta = -40 to 125° C, Vcc = 4.5 to 5.5V)

Characteristic	Symbol	Test Circuit	Test Conditions	Min	Typ.*) Max	Unit
Input forward current	VF		I _F = 10 mA, Ta = 25 °C	1.40	1.57	1.80	V
Temperature coefficient of forward voltage	ΔV _F /ΔTa	1	I _E = 10 mA		-1.8	_	mV/°C
Input reverse current	IR		V _R = 5 V, Ta = 25 °C) —	_	10	μΑ
Input capacitance	CT	ST.	V _F = 0 V, f = 1 MHz, Ta = 25 °C		60	_	pF
	($V_F = 0.8 \text{ V}, V_O = 5.5 \text{ V}$		_	250	
"H" level output current	Іон		$V_F = 0.8 \text{ V}, V_O = 5.5 \text{ V}$ Ta = 25 °C	_	0.5	10	μΑ
"L" level output voltage	(Vol.)	2	I _F = 10 mA, I _{OL} = 13 mA (sink)	_	0.3	0.6	V
Input threshold current	JEHL .	_	IOL = 13 mA (sink), VO < 0.6 V	_	1.5	5.0	mA
"H" level supply current	Госн	3 /	IF = 0 mA	_	1.5	5.0	mA
"L" level supply current	ICCL	4	VF = 10 mA		1.4	5.0	mA

^{*}All typical values are at Ta = 25 °C, V_{CC} = 5 V unless otherwise specified.

Isolation Characteristics (Ta = 25°C)

Characteristic	Symbol	Test Conditions	Min	Тур.	Max	Unit
Capacitance input to output	Cs	V _S = 0 V, f = 1 MHz	_	0.8	_	pF
Isolation resistance	Rs	R.H. ≤ 60 %,V _S = 500 V	10 ¹²	10 ¹⁴	1	Ω
Isolation voltage	BVS	AC,60 s	5000		1	V _{rms}

Note: This device is regarded as a two-terminal device: pins 1, 2 and 3 are shorted together, and pins 4, 5 and 6 are shorted together.

Switching Characteristics

(Unless otherwise specified, Ta = -40 to $125^{\circ}C$, $V_{CC} = 4.5$ to 5.5 V)

Characteristic	Symbol	Test Circuit	Test Cor	Min	Тур.*	Max	Unit	
Propagation delay time to logic low output	t _{pHL}		I _F = 0→7.5 mA	R _L = 350 Ω		35	75	ns
Propagation delay time to logic high output	t _{pLH}		I _F = 7.5→0 mA	C _L = 15 pF (Note 4)		35	75	ns
Switching time dispersion between ON and OFF	t _{pHL} - t _{pLH}	5	I _F = 0↔7.5 mA	R _L = 350 Ω C _L = 15 pF	(7 / 5)	12	35	ns
Propagation delay skew (Note 5)	tpsk			(Note 4)	-50		50	ns
Output fall time (90-10%)	t _f		I _F = 0→7.5 mA	$R_L = 350 \Omega$)>-	6	1	ns
Output rise time(10-90%)	tr		I _F = 7.5→0 mA	C _L = 15 pF (Note 4)	_	18		ns
Common mode transient immunity at high level output	СМН		$V_{CM} = 1000 V_{p-p}$ $V_{CC} = 5 V, Ta = 2$		+15		> >	kV/µs
Common mode transient immunity at low level output	CML	6	V _{CM} = 1000 V _{p-p} , I _F = 10 mA, V _{CC} = 5 V, Ta = 25 °C		-15	70) _	kV/µs

^{*}All typical values are at Ta=25°C

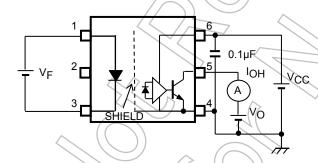
Note 3: A ceramic capacitor (0.1 μ F) should be connected from pin 6 (V_{CC}) to pin 4 (GND) to stabilize the operation of the high gain linear amplifier. Failure to provide the bypass may impair the switching property. The total lead length between the capacitor and coupler should not exceed 1 cm.

Note 4: f = 5 MHz, duty=50 %, input current $t_r = t_f = 4.5$ ns,

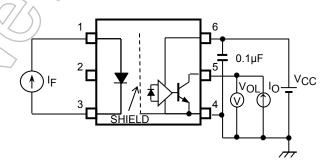
C_L is less than 15 pF which includes probe and jig/stray wiring capacitance.

Note 5 Propagation delay skew is defined as the difference between the largest and smallest propagation delay times (i.e. t_{pHL} or tpLH) of multiple samples. Evaluations of these samples are conducted under identical test conditions (supply voltage, input current, temperature, etc).

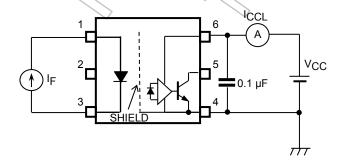
TEST CIRCUIT 1: IOH Test Circuit



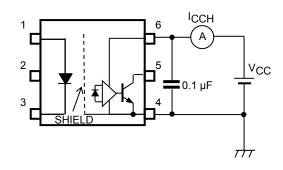
TEST CIRCUIT 2: Vol Test Circuit



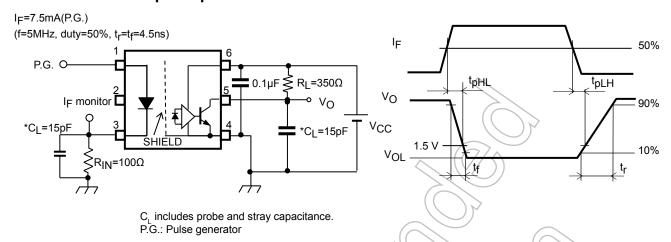
TEST CIRCUIT 3: Iccl Test Circuit



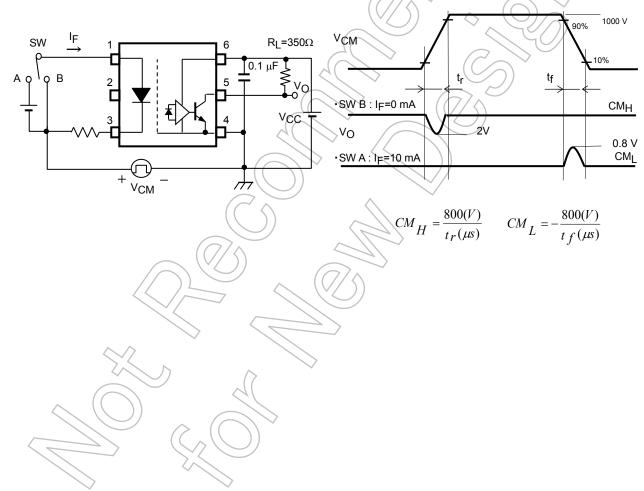
TEST CIRCUIT 4: Icch Test Circuit

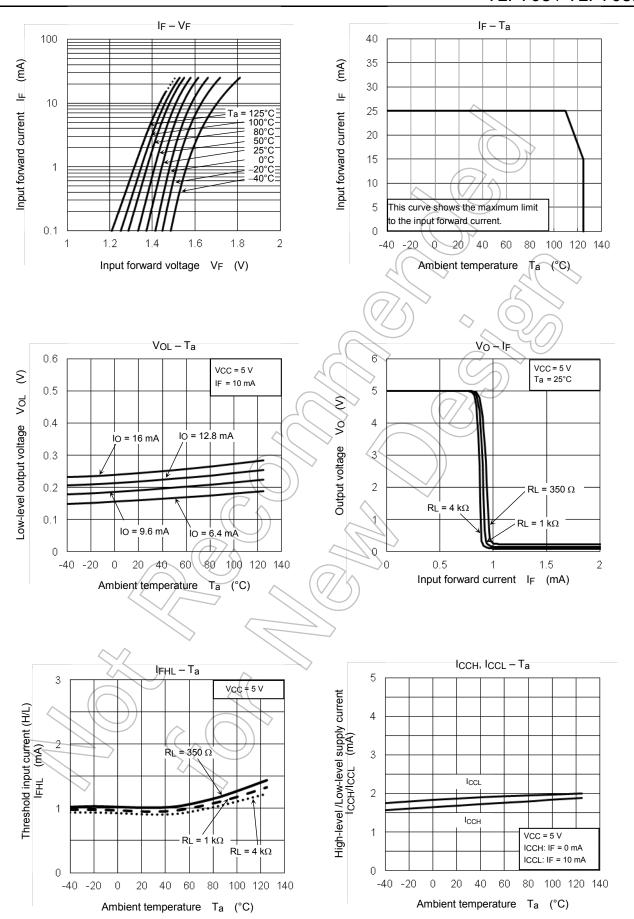


TEST CIRCUIT 5: tpHL, tpLH Test Circuit

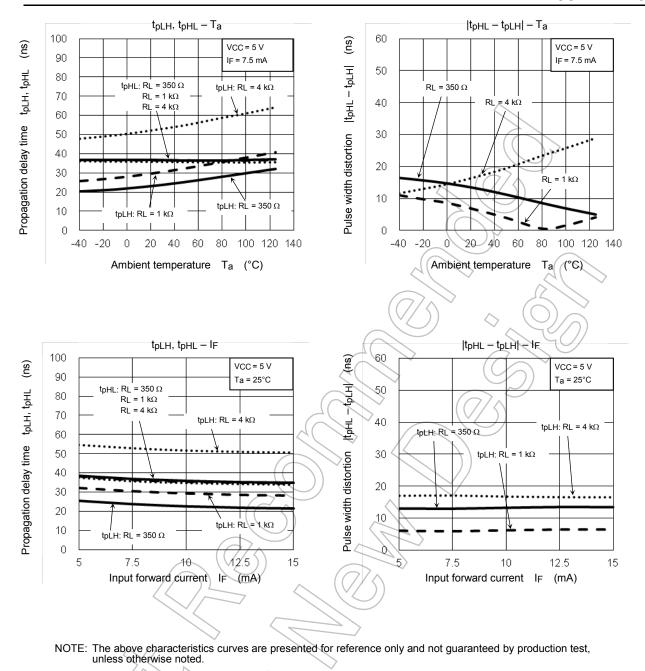


TEST CIRCUIT 6: Common-Mode Transient Immunity Test Circuit





NOTE: The above characteristics curves are presented for reference only and not guaranteed by production test, unless otherwise noted.



Soldering and Storage

(1) Precautions for Soldering

The soldering temperature should be controlled as closely as possible to the conditions shown below, irrespective of whether a soldering iron or a reflow soldering method is used.

1) When Using Soldering Reflow

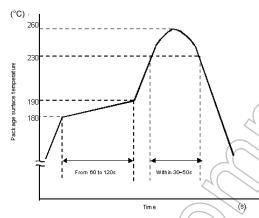
The soldering temperature profile is based on the package surface temperature.

(See the figure shown below, which is based on the package surface temperature.)

Reflow soldering must be performed once or twice.

The mounting should be completed with the interval from the first to the last mountings being 2 weeks.

An example of a temperature profile when lead(Pb)-free solder is used:



This profile is based on the device's maximum heat resistance guaranteed value.

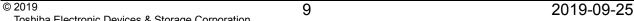
Set the preheat temperature/heating temperature to the optimum temperature corresponding to the solder paste type used by the customer within the described profile.

- 2) When using soldering flow
 - Preheat the device at a temperature of 150 °C (package surface temperature) for 60 to 120 seconds.
 - Mounting condition of 260 °C within 10 seconds is recommended.
 - Flow soldering must be performed once
- 3) When using soldering Iron
 - Complete soldering within 10 seconds for lead temperature not exceeding 260 °C or within 3 seconds not exceeding 350 °C.
 - Heating by soldering iron must be only once per 1 lead



(2) Precautions for General Storage

- 1) Do not store devices in places where they will be exposed to moisture or direct sunlight.
- 2) During transportation or storage of devices, follow the cautions indicated on the carton box.
- 3) The storage area temperature should be kept within a temperature range of 5°C to 35°C, and the relative humidity should be maintained between 45% and 75%.
- 4) Do not store devices in the presence of harmful (especially corrosive) gases, or under dusty conditions
- 5) Use storage areas where there is minimal temperature fluctuation. The solderability of the leads will be degraded as rapid temperature changes can cause condensation to form on the stored devices, resulting in lead oxidation or corrosion.
- 6) When repacking devices, use anti-static containers.
- 7) Do not apply any external force or load directly to devices when they are in storage.
- 8) If devices have been stored for more than two years, it is recommended that their solderability be tested before they are used even if the above precautions have been followed.





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